



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16552Generic Copy

Issue Date: 29-Jul-2011

TITLE: Release of an additional tester platform (Micro Flex) for the C623/C624-SO Package (currently tested on TMT tester platform)

PROPOSED FIRST SHIP DATE: 29-Oct-2011 or earlier after Final PCN approval by customer (target date: 15-Aug-2011)

AFFECTED CHANGE CATEGORY(S): Final test and QC insertions

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office, your customer quality interface or Xavier Van Esch (xavier.vanesch@onsemi.com)

SAMPLES: Contact your local ON Semiconductor Sales Office

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

Release of Micro FLEX tester platform for Final Test and QC to improve tester capacity balancing and loading.

Qualification data:

QC ambient correlation data between the source tester (TMT) and the target tester (Micro FLEX) is provided in a separate qualification report (0C623-010_TMT-uFlex_correlation_report.doc) together with this Final PCN.

The correlation procedure has been used, like done as in previous PCN's covering the release of additional tester platforms

- 2 correlation units have been serialized and datalogged in 30 loops using the source tester platform where the device is already qualified. The test was be done at room temperature, using the QC program.
- Then, the same correlation units were used to gather data on target tester microFLEX.
- The same datalogging procedure used for TMT has been followed for microFLEX.



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16552

Full parametric correlation will be performed and for every test the shift will be evaluated as follows:

$$\Delta\text{mean} = \text{abs}(\text{mean}(\text{ref}) - \text{mean}(\text{qual}))$$

$$\Delta\text{sigma} = 0$$

$$\Delta\text{sigma} = \text{sigma}(\text{qual}) - \text{sigma}(\text{ref})$$

$$\text{if } \text{sigma}(\text{qual}) < \text{sigma}(\text{ref})$$

$$\text{if } \text{sigma}(\text{qual}) > \text{sigma}(\text{ref})$$

$$\text{shift} = \Delta\text{mean} + 4 * \Delta\text{sigma}$$

**If shift < max(5% specwidth, 6*sigma(ref)) then correlation is OK for this test,
else correlation is NOK for this test**

Any parameter that is NOK is independently analysed and explained.

ELECTRICAL CHARACTERISTIC SUMMARY:

Electrical Performance will continue to meet specifications.

List of affected Standard Parts:

Internal ONSEMI Sellable Code	External ONSEMI Sellable Code
0C623-008-XTD	AMIS30623C6238G
0C623-008-XTP	AMIS30623C6238RG
0C624-010-XTD	NCV70624DW010G
0C624-010-XTP	NCV70624DW010R2G